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FOR IMMEDIATE RELEASE

SyntheSys Research Demonstrates HDEYE292 High Definition Video Test System AT SMPTE2000 Technical Conference

Pasadena, Calif.—October 18, 2000—SyntheSys Research, Inc., the leader in providing advanced digital audio-visual test and measurement equipment for the television and telecommunications markets, is demonstrating the HDEYE292 High Definition Video Test System—the most comprehensive combination analysis and generation test system available for high-definition serial digital signals (SMPTE292M). The product assists engineers, technicians, and users who design, evaluate, and maintain high-definition audio-visual systems for manufacturing, production, broadcast, and transport. The system is being demonstrated during the 142nd SMPTE Technical Conference & Exhibition at the Pasadena Center.

The new analyzer offers the most comprehensive combination high-definition analysis and signal-generation test system available for the television and telecommunications industries.

The new analyzer supports 14 HDTV formats including film-oriented “Segmented Frame” formats. With the addition of the optional signal generator function, the HDEYE292 is capable of both stimulating and evaluating high-definition systems in all formats. The analyzer performs both format-level and physical-level testing, including the world’s first eye diagram and jitter spectrum analysis features for the 1.485 Gbps high-definition SMPTE 292M signal.

“As high-definition serial digital systems become increasingly prevalent in broadcast and post production facilities,” said Jim Waschura, video product line manager, “the quality and integrity of those signals become all-important. Testing these paths as they are routed through various locations throughout the plant will be extremely important to insure that format and signal compliance of the high-definition serial digital signal are maintained throughout. We developed the HDEYE292 analyzer to assure that both signal format and compliance remain consistent, and provide the user with results that are intuitive and designed to direct the user towards the problem area.”

For price and availability please contact SyntheSys Research, Inc. via its website at www.synthesysresearch.com.

The system includes eye diagram display of serial waveform, FFT analysis of jitter, automatic measurements of the waveform parameters, and tests for format layer protocol compliance to SMPTE292M. An optional test pattern generator generates test patterns to stimulate systems under test in both normal and stressed conditions.

The HDEYE292 also tests SMPTE 292M signals for physical layer impairments, including signal distortions and increased jitter caused by faulty equipment, cables, connectors, long cable runs, and data dependent errors caused by the transmission of “pathological” test patterns.

About SyntheSys Research, Inc.

SyntheSys Research, Inc., supplies advanced digital channel error analysis instruments to the communications, recording and digital video industries. A privately held California corporation founded in 1989, the company’s mission is to develop new, advanced test instruments in high-speed electronics, highly integrated microprocessors, and software. SyntheSys’ patented

BitAlyzer® analyzers study the location of errors in a data stream in addition to counting errors, providing more detailed information for engineers to discover the source of errors. Major global clients owning SyntheSys products include ABC (US), Allied Signal, Boeing, CBS, CNN, Fujitsu, Harris, HBO, Hitachi, Hughes, IBM, Lucent, NASA, National Semiconductors, NEC, Samsung, Sony, Tektronix, TRW, US Air Force and the US Navy. For further information, call (650) 364-1853 or see the company website at www.synthesysresearch.com.

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